Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/786,072	ISHII ET AL.	
Examiner	Art Unit	
Patrick A. Darno	2163	

SEARCHED			
Class	Subclass	Date	Examiner
707	009	4/26/2005	PAD
718	104	4/26/2005	PAD
340	5.28	4/26/2005	PAD
709	218	4/26/2005	PAD
709	104	4/26/2005	PAD
709	229	4/26/2005	PAD
455	410	4/26/2005	PAD

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH I (INCLUDING SEAR		Y)
	DATE	EXMR
EAST	4/26/2005	PAD
Consulted Etienne LeRoux	4/25/2006	PAD
Consulted Hal Dodds	4/25/2006	PAD
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